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IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

IN RE APPLICATION OF: Joseph T. VERDEYEN et al.

SERIAL NO.: NEW U.S. PCT APPLICATION

FILED: HEREWITH

INTERNATIONAL APPLICATION NO.: PCT/US00/19536

INTERNATIONAL FILING DATE: July 20, 2000

FOR: ELECTRON DENSITY MEASUREMENT AND PLASMA PROCESS CONTROL SYSTEM
USING CHANGES IN THE RESONANT FREQUENCY OF AN OPEN RESONATOR
CONTAINING THE PLASMA

REQUEST FOR PRIORITY UNDER 35 U.S.C. 119(e)
AND THE INTERNATIONAL CONVENTION

Assistant Commissioner for Patents
Washington, D.C. 20231

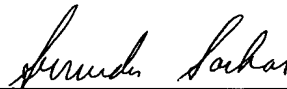
Sir:

In the matter of the above-identified application for patent, notice is hereby given that
the applicant claims as priority:

<u>COUNTRY</u>	<u>APPLICATION NO</u>	<u>DAY/MONTH/YEAR</u>
USA	60/144,833	21 July 1999

Certified copies of the corresponding Convention application(s) were submitted to the
International Bureau in PCT Application No. PCT/US00/19536.

Respectfully submitted,
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